Form PTO-1449 (Substitute)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number LAZE-01019US1	Serial/Patent Number 10/685,045
	Information Disclosure Statement BY APPLICANT (*Use several sheets if necessary*)	Applicant/Patent Owner Thomas F. Rust	
		Filing/Issue Date 10/14/2003	Group Art Unit 2824

U.S. PATENT & TRADEMARK OFFICE JUN 16 2004

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		Filing/Issue Date October 14, 2003	Group Art Unit 2824

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